Real-time Photonic Measurements, Data Management, and Processing III

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Bahram Jalali
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Editors

12–13 October 2018
Beijing, China

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SPIE

Volume 10822

Proceedings of SPIE 0277-786X, V. 10822

Real-time Photonic Measurements, Data Management, and Processing III, edited by Ming Li,
Bahram Jalali, Keisuke Goda, Kevin K. Tsia, Proc. of SPIE Vol. 10822, 1082201 · © 2018
SPIE · CCC code: 0277-786X/18/$18 · doi: 10.1117/12.2521080

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Please use the following format to cite material from these proceedings:
Author(s), "Title of Paper," in *Real-time Photonic Measurements, Data Management, and Processing III*, edited by Ming Li, Bahram Jalali, Keisuke Goda, Kevin K. Tsia, Proceedings of SPIE Vol. 10822 (SPIE, Bellingham, WA, 2018) Seven-digit Article CID Number.

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510622425
ISBN: 9781510622432 (electronic)

Published by
SPIE
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445
SPIE.org

Printed in the United States of America.

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